

SAMPA MPW1 tests

Weekly report

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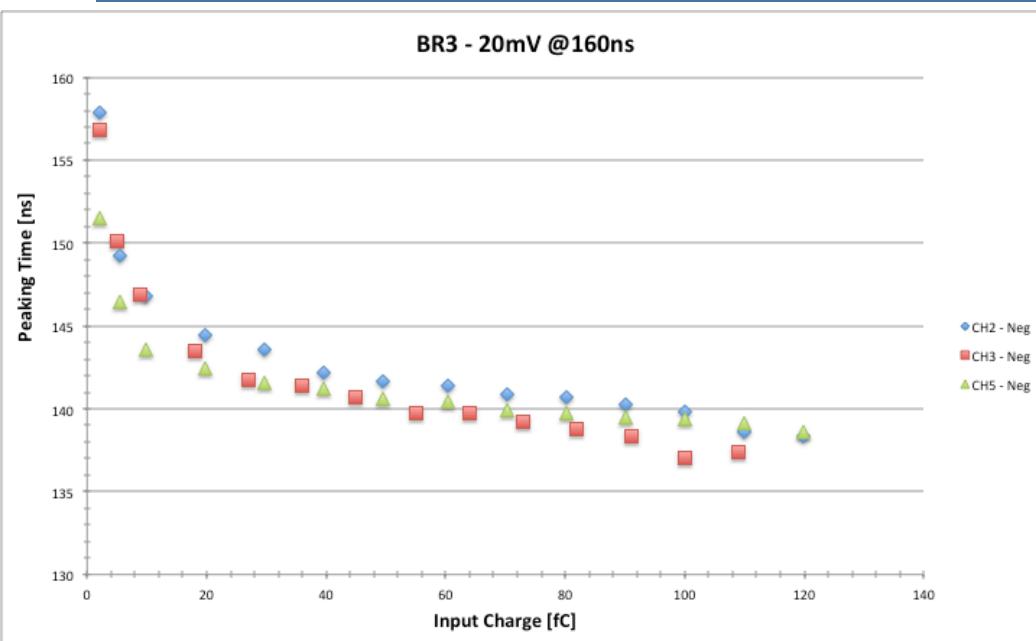
Universidade de São Paulo



Measurement Results: MPW1-Chip1-Board 3

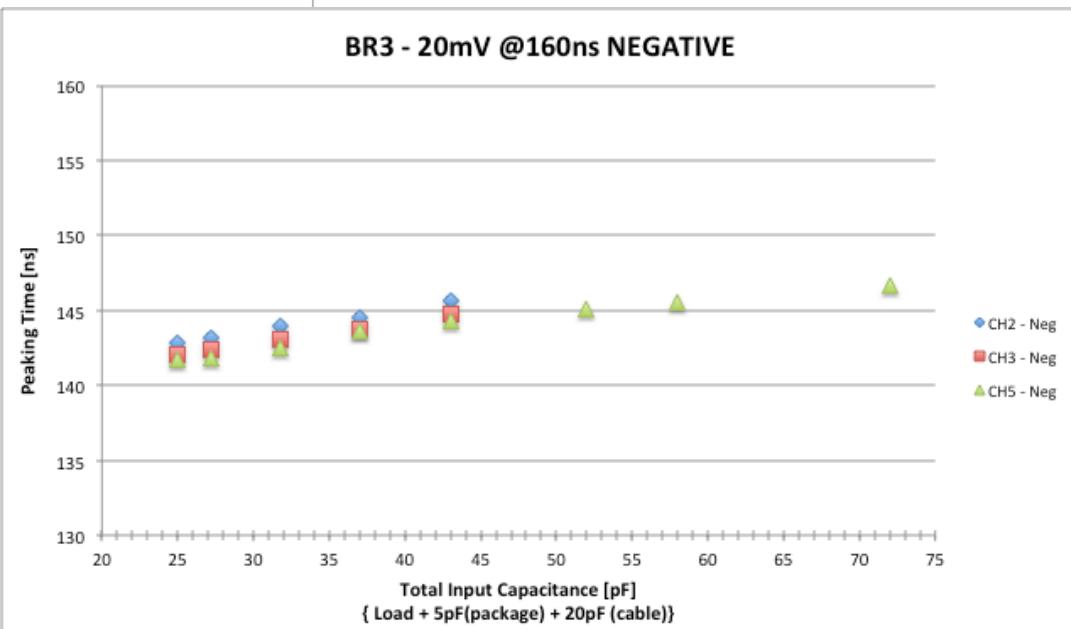
- Measurements performed for the 5 configurations:
 - 20mV@160ns NEGATIVE & POSITIVE
 - 30mV@160ns NEGATIVE & POSITIVE
 - 4mV @ 300ns POSITIVE
- Peaking Time vs Input Charge
- Peaking Time vs Detector Capacitance
- ENC vs Capacitance with Bergen's measurement

20mV/fC @ 160ns – Peaking Time

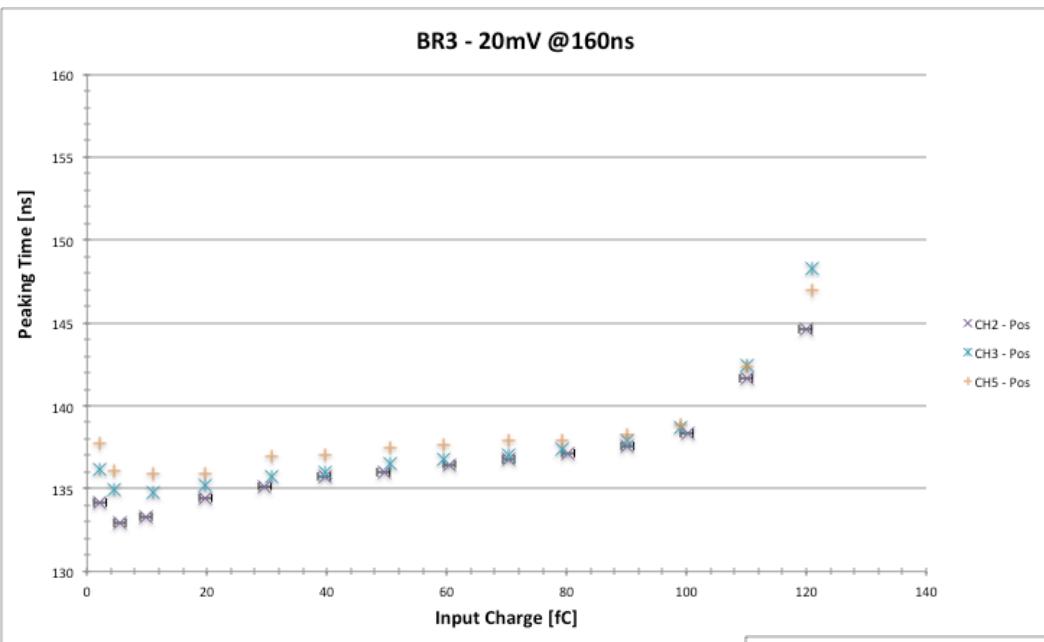


- Input Capacitance = 5pF (chip package) + 1ns LEMO Cable (20pF)
- All other channels with a 20pF load
- Error = \pm sigma of the measurement

Input Charge = 50.6fC

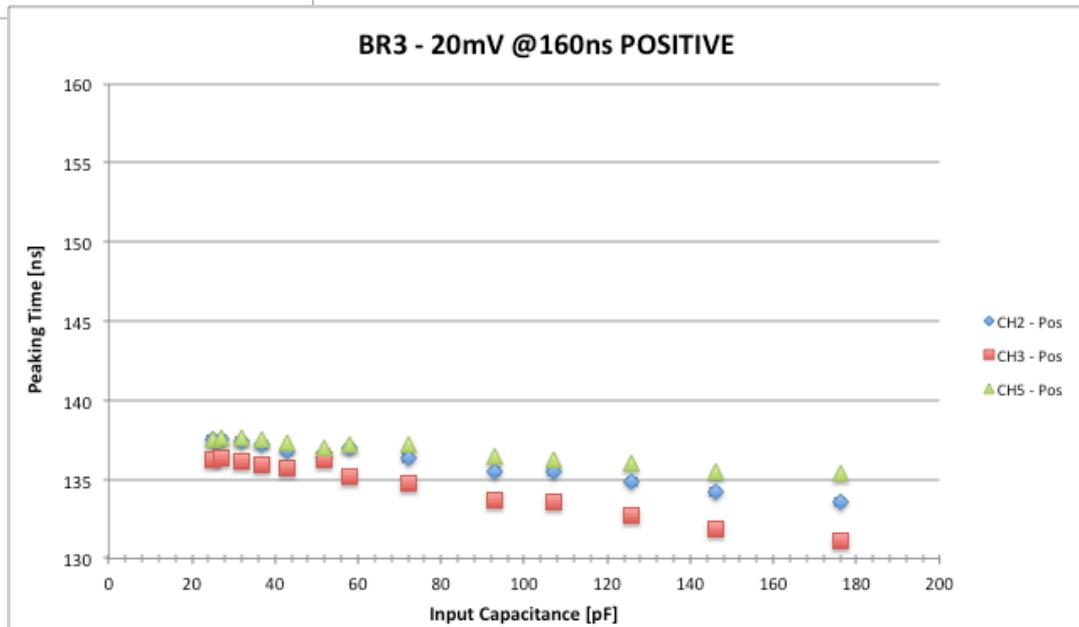


20mV/fC @ 160ns – Peaking Time

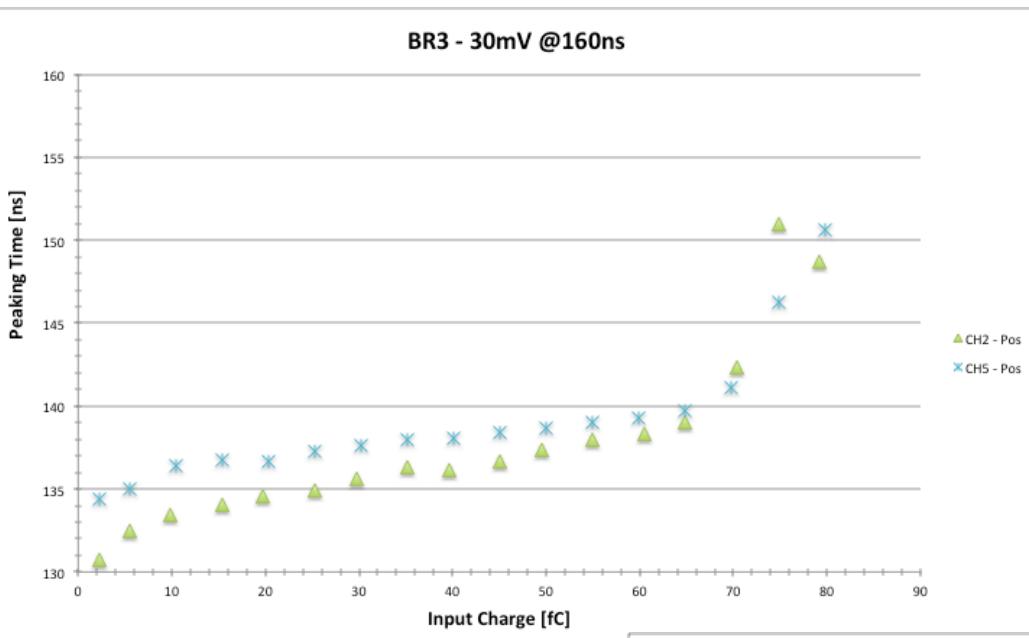


- Input Capacitance = 5pF (chip package) + 1ns LEMO Cable (20pF)
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- Error = \pm sigma of the measurement

Input Charge = 50.6fC

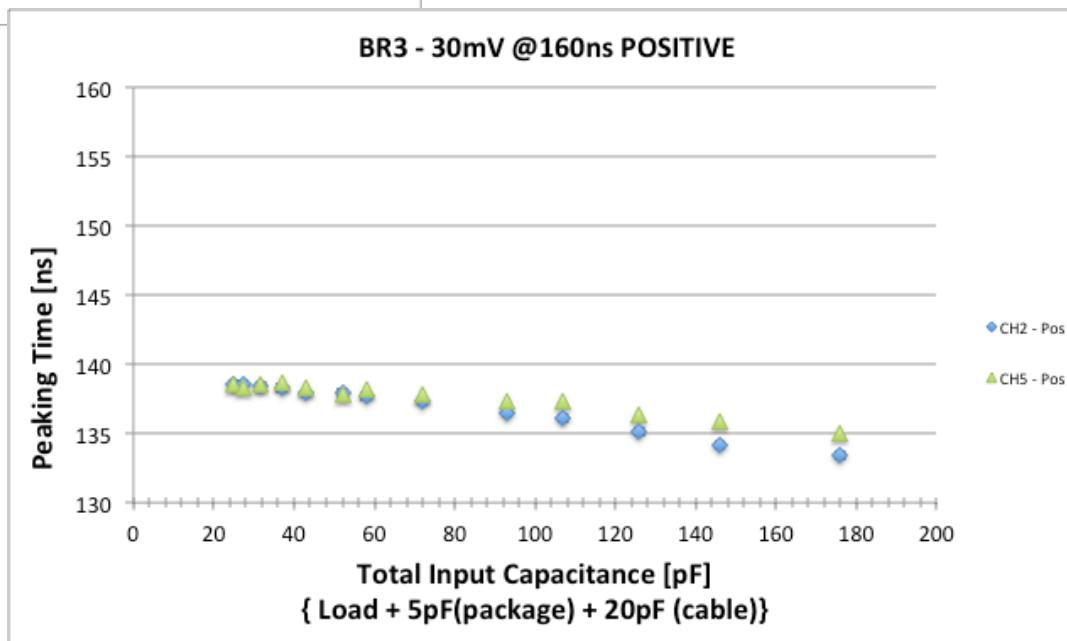


30mV/fC @ 160ns – Peaking Time

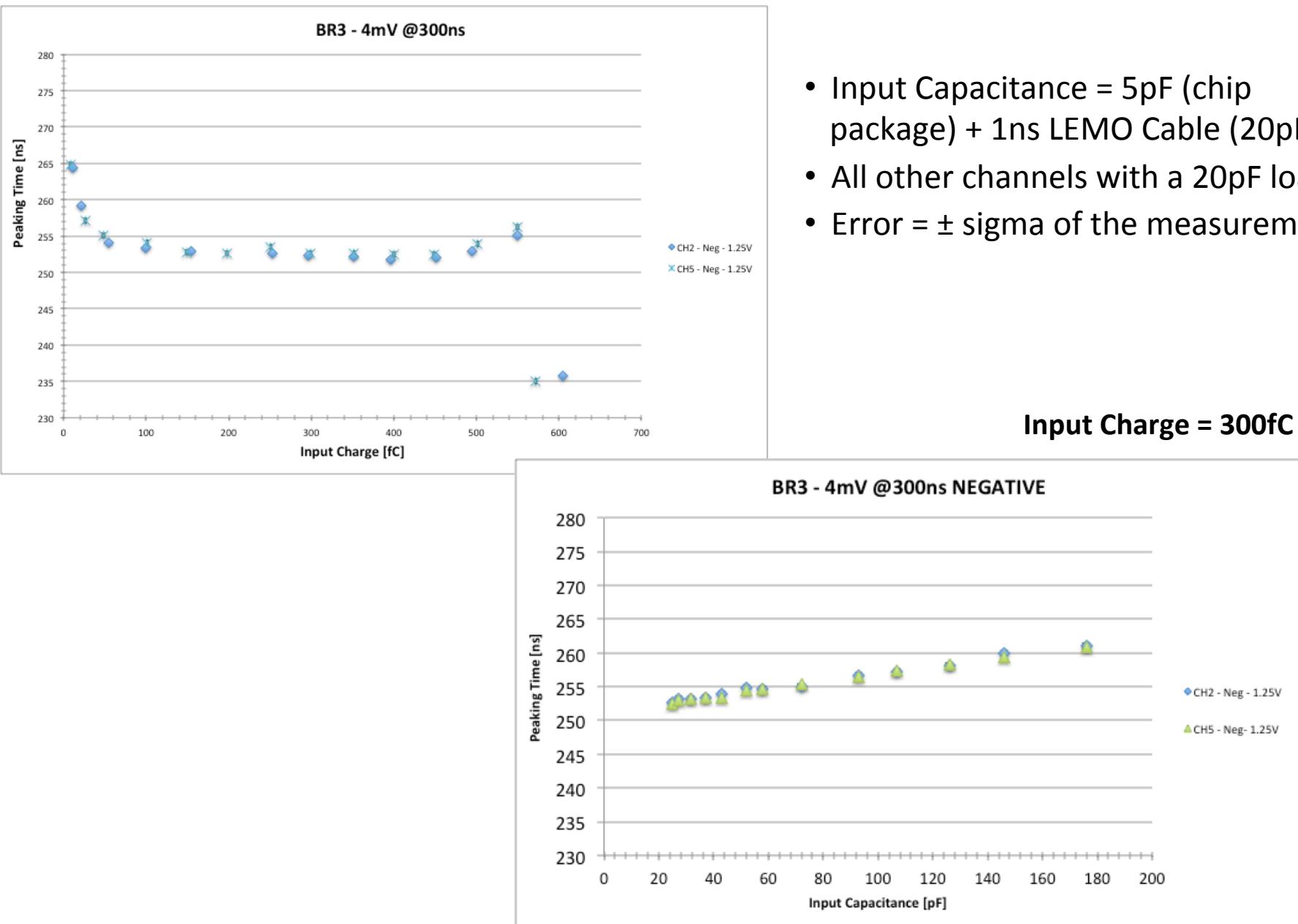


- Input Capacitance = 5pF (chip package) + 1ns LEMO Cable (20pF)
- All other channels with a 20pF load
- Error = \pm sigma of the measurement

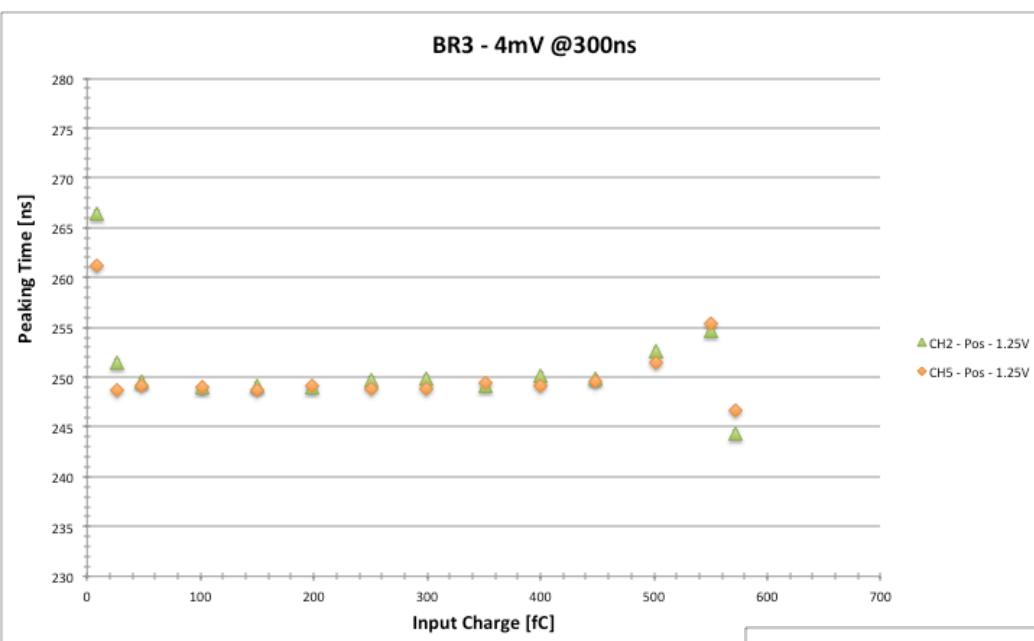
Input Charge = 50.6fC



4mV/fC @ 300ns – Peaking Time

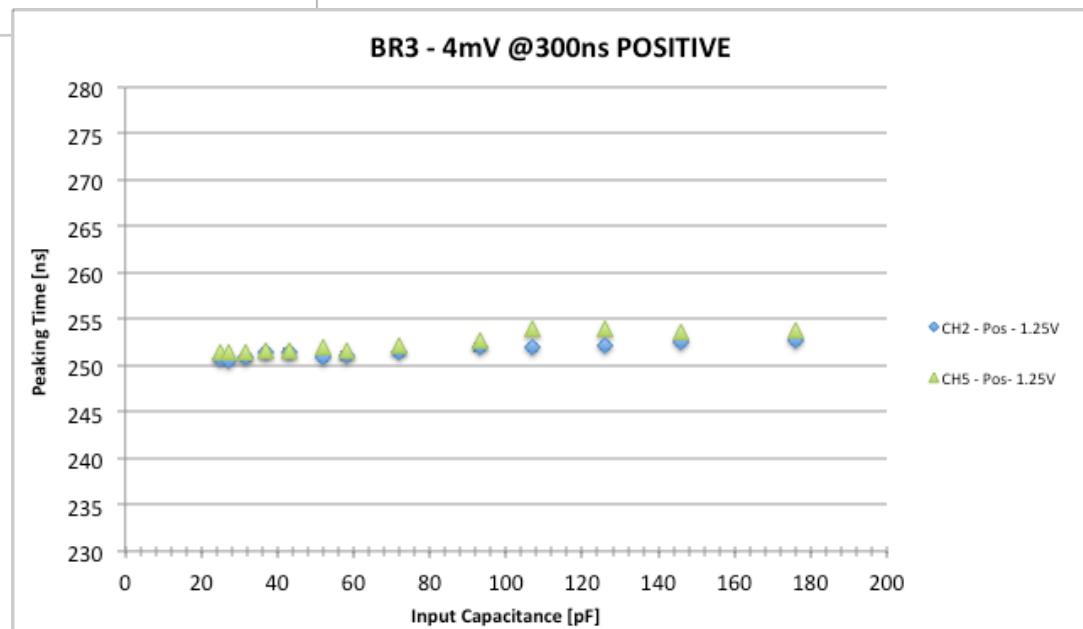


4mV/fC @ 300ns – Peaking Time

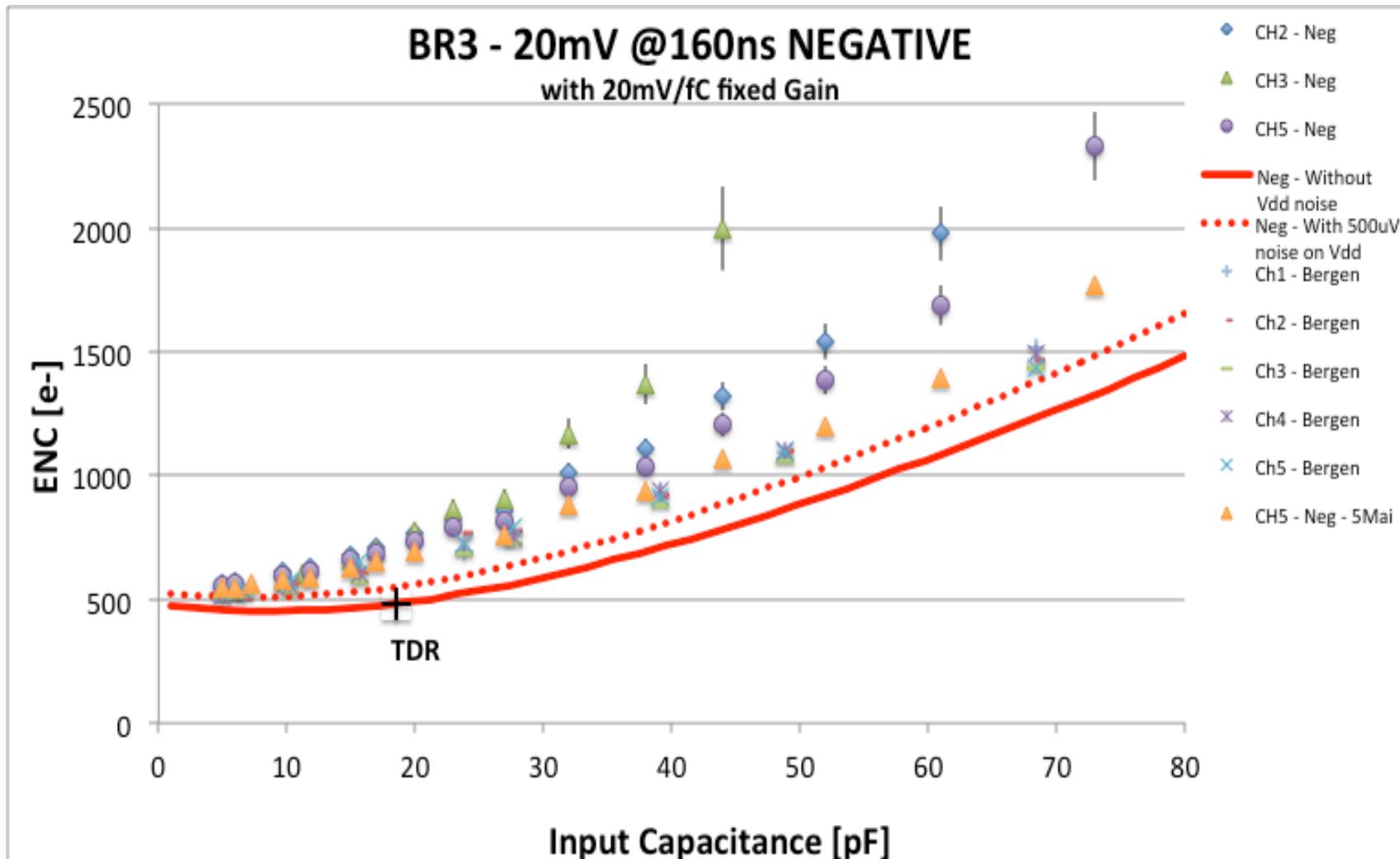


- Input Capacitance = 5pF (chip package) + 1ns LEMO Cable (20pF)
- All other channels with a 20pF load
- Error = \pm sigma of the measurement

Input Charge = 300fC

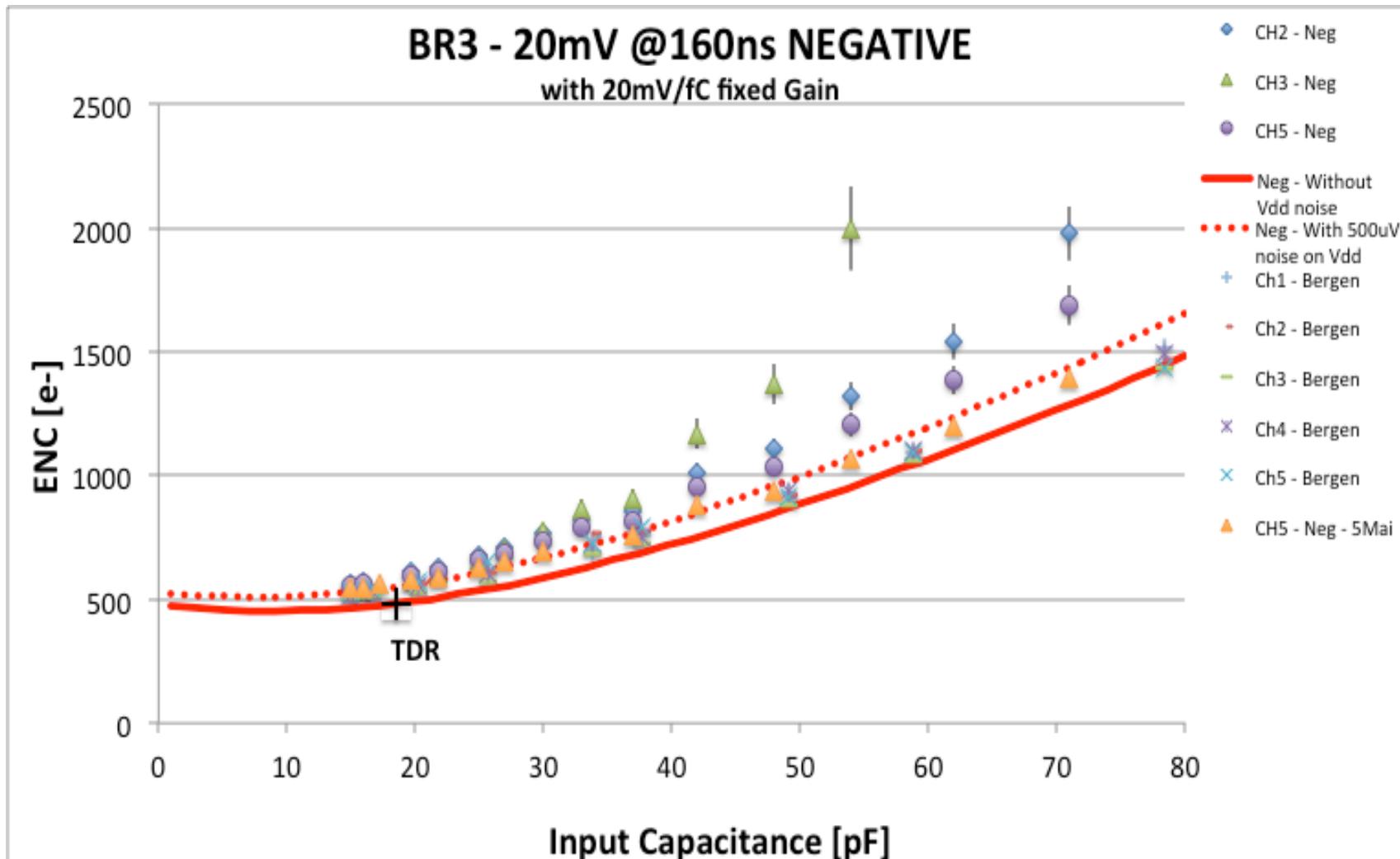


20mV/fC @ 160ns – Noise



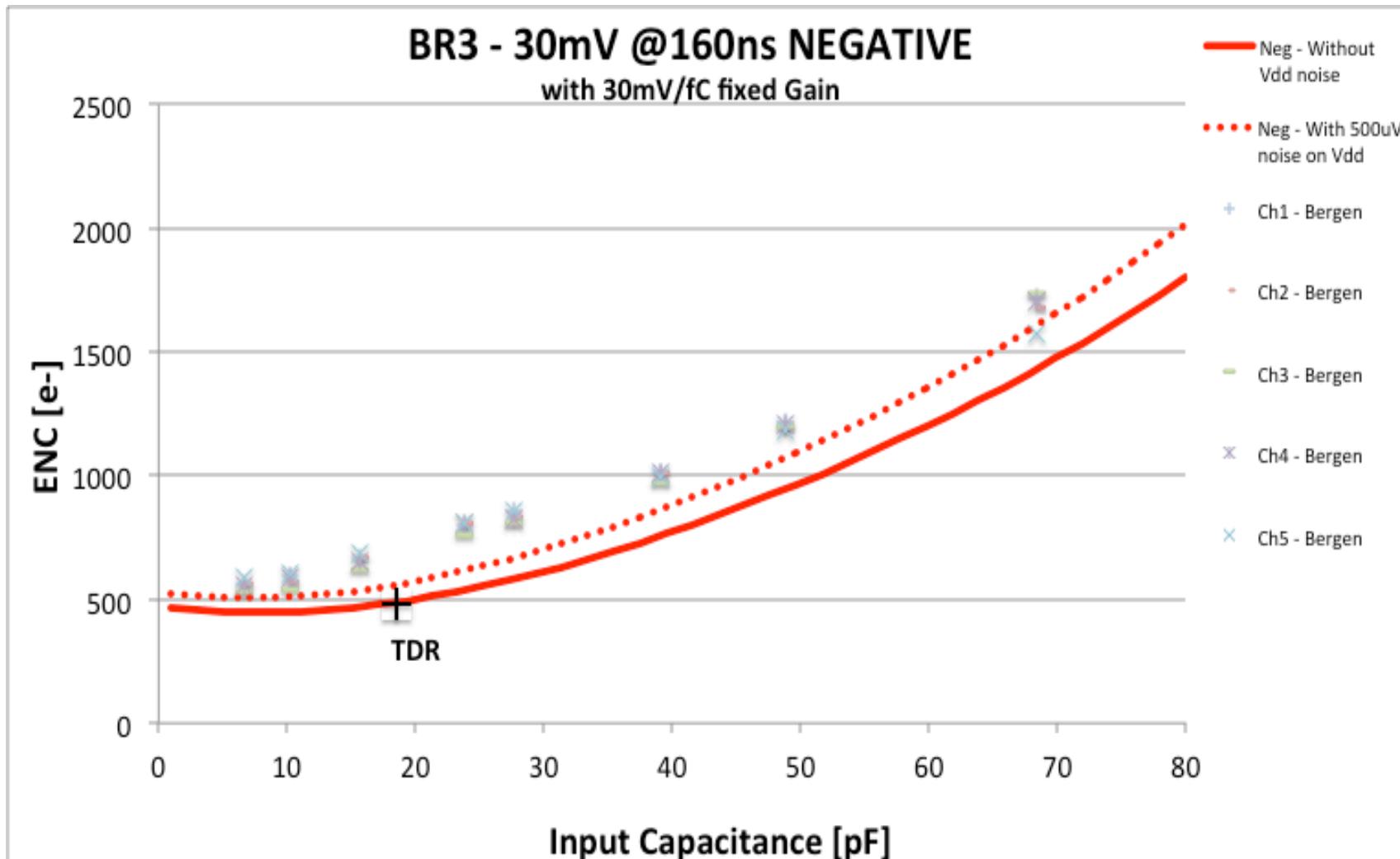
Considering 5pF (chip package)

20mV/fC @ 160ns – Noise



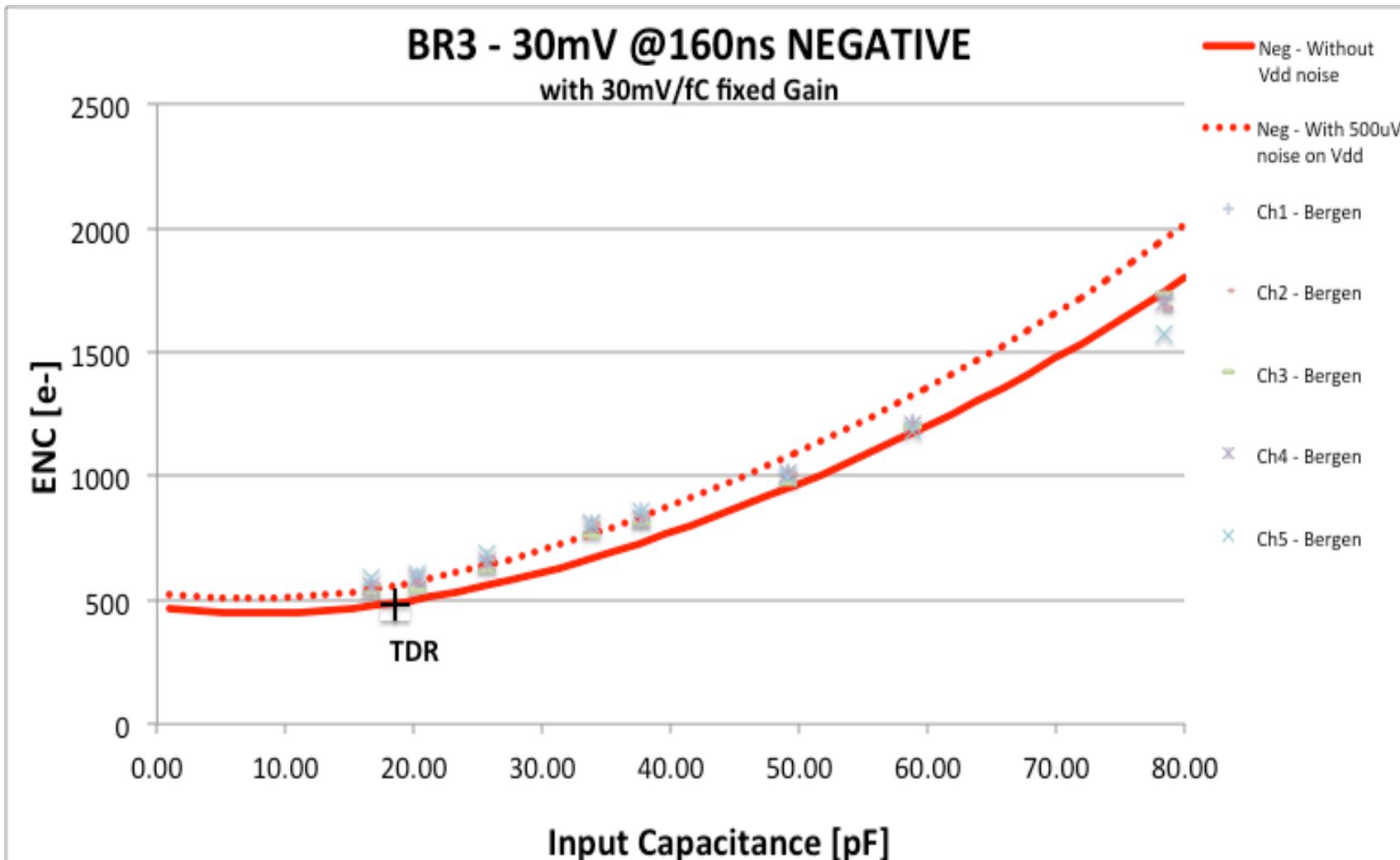
Considering 5pF (chip package) + 10pF (board+ connector)

30mV/fC @ 160ns – Noise



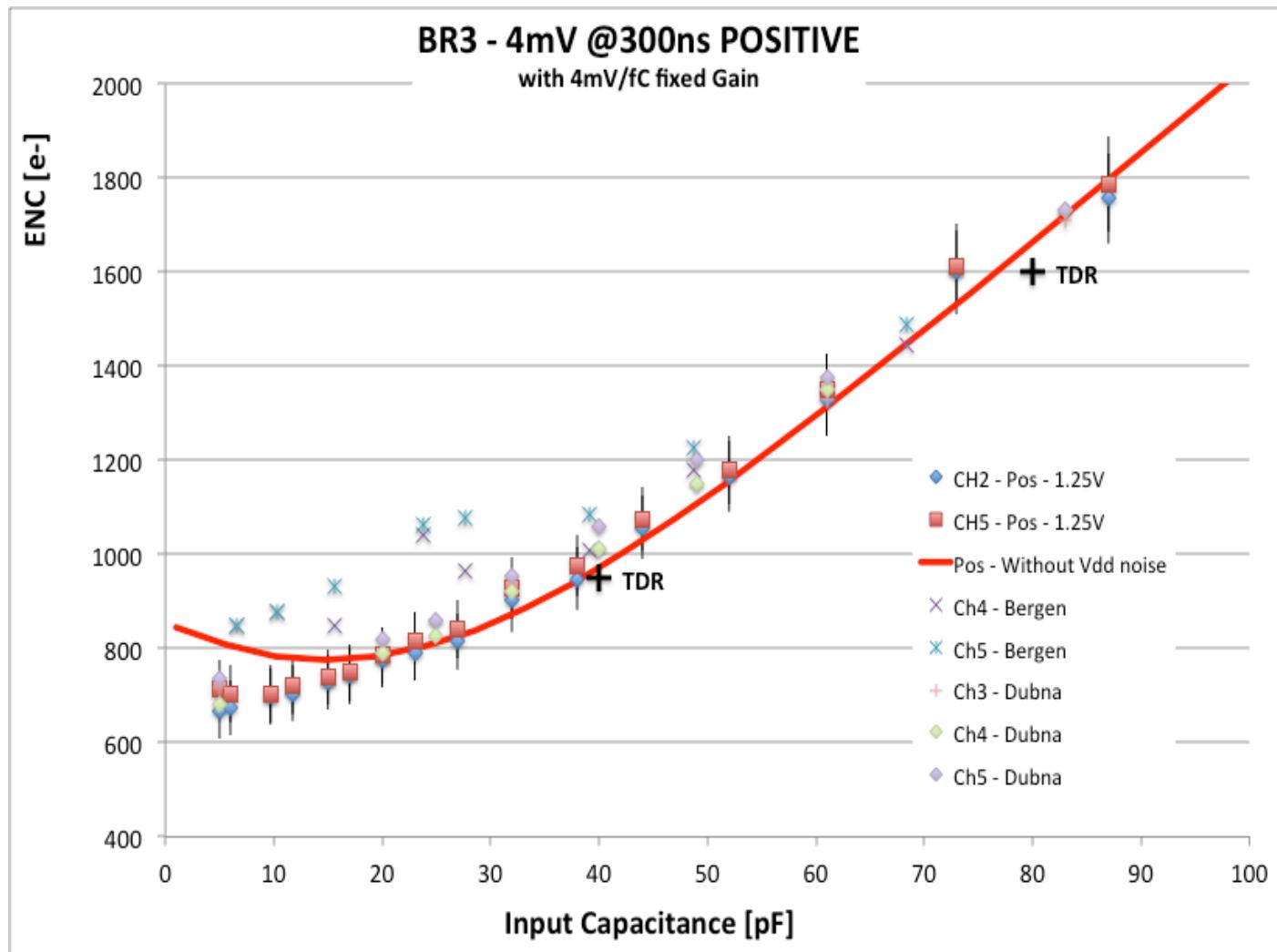
Considering 5pF (chip package)

30mV/fC @ 160ns – Noise



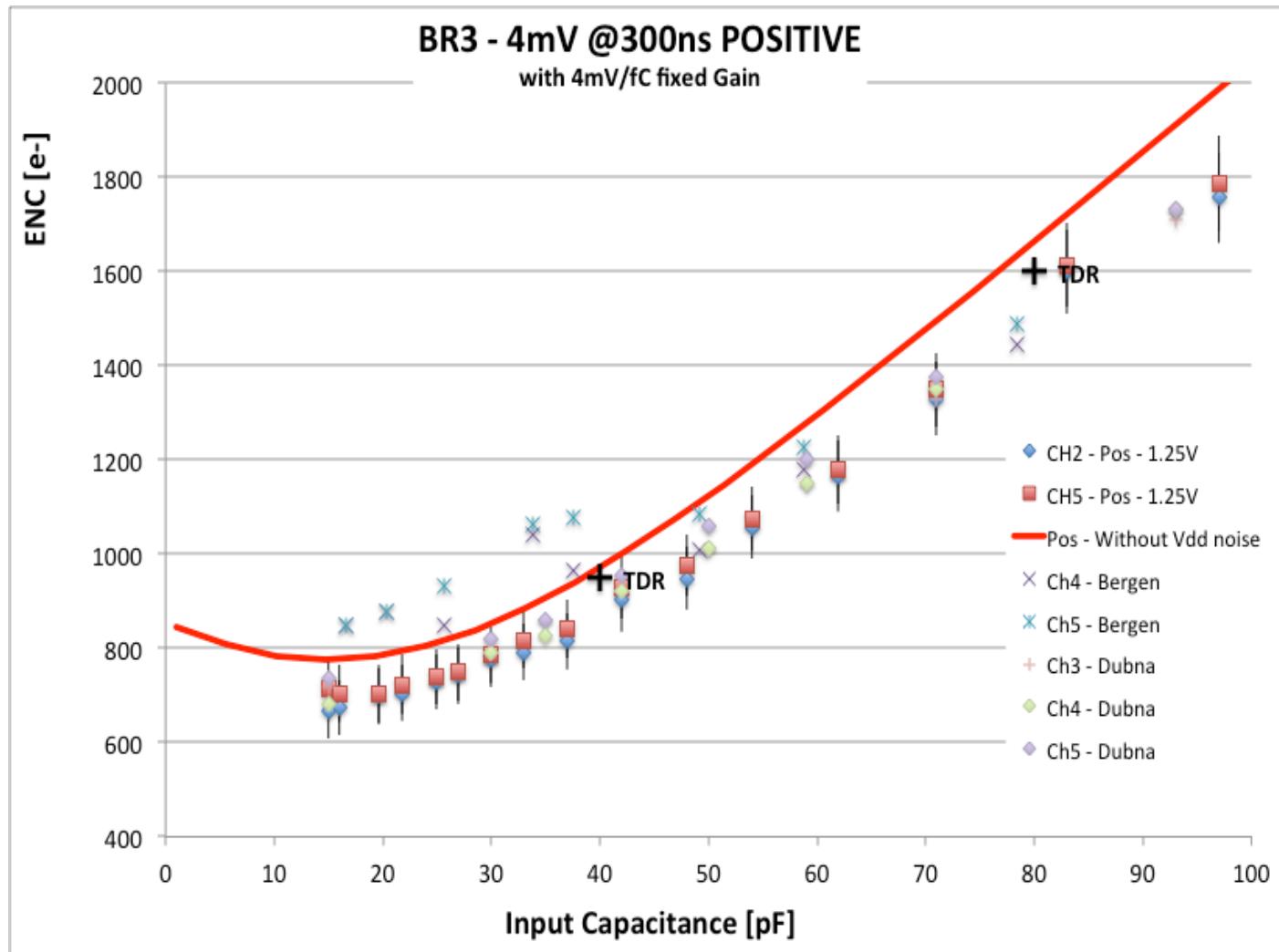
Considering 5pF (chip package) + 10pF (board+ connector)

4mV/fC @ 300ns – Noise



Considering 5pF (chip package)

4mV/fC @ 300ns – Noise



Considering 5pF (chip package) + 10pF (board+ connector)